	U.S.PATENT DOCUMENTS					
Ref. Desig,	Examiner's Initials	Document Number	Date	Name	Class/ Subclass	(If appropriate) Filing Date
	CH	6,571,647	6/3/03	Aoki et al. (corres. to JP 2000-258234)		
					 	
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Ref.	Examiner's	Document			Class/		
Desig,	Initials	Number	Date	Country	Subclass	Yes	No
	CH	9-207638 (discussed on page 1 in the spec.)	8/12/97	Japan		Х	
	M	2000-258234 (discussed on page 2 in the spec.)	9/22/00	Japan			
	M	2002-243528 (discussed on page 1 in the spec.)	8/28/02	Japan		X	
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		OTHER DOCUMENTS (including Author, Title, Date, Pertinent	t Pages, etc.)	
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Desig,	Initials		·	
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EXAMINER:		Date Considered: 12/13/04

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